

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Shoichiro CHIBA et al.

Appln. No.:

Group Art Unit:

Filed: HEREWITH

For: DATA PROCESSOR

\* \* \*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The Japanese documents on the attached List were cited in the specification, on page 3, and their relevance is indicated therein. Document AA is the U.S. counterpart of Document AJ. Document AB is the U.S. counterpart of Document AK. Document AC is the U.S. counterpart of Document AL. Document AF is the U.S. counterpart of Document AN.

Respectfully submitted,

MWS:sys

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March 30, 2004

<b>FORM PTO-1449</b>				Atty. Docket No. <b>XA-10064</b>		Appln. No.	
<b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>							
				Applicant <b>Shoichiro CHIBA et al.</b>			
				Filing Date <b>HEREWITH</b>		Group	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	5,581,503	12/03/96	Matsubara et al.	365	185.33	
	AB	6,201,733 B1	03/13/01	Hiraki et al.	365	185.08	
	AC	5,561,627	10/01/96	Matsubara et al.	365	185.04	
	AD	4,659,828	04/21/87	Fong	544	399	
	AE	5,408,115	04/18/95	Chang	257	324	
	AF	6,046,936	04/04/00	Tsujikawa et al.	365	185.03	
	AG						
	AH						
	AI						
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AJ	5-266219	10/15/93	Japan			No
	AK	2000-149588	5/30/00	Japan			No
	AL	7-334999	12/22/95	Japan			No
	AM	5-136422	06/01/93	Japan			Abstract
	AN	11-232886	08/27/99	Japan			No
	AO						
<b>OTHER</b> (including author, title, date, pertinent pages, etc.)							
	AP	Sohrab Kianian et al., "A Novel 3 Volts-Only, Small Sector Erase, High Density Flash E2PROM", IEEE, VLSI Technology Symposium, 1994 proceedings", pp. 71 - 72.					
	AQ						
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							